

CE EMC TEST REPORT

Report No.: DDT-B23020606-1E01

Applicant	:	TPV Electronics (Fujian) Co., Ltd.
Address	:	Rongqiao Economic and Technological Development Zone, Fuqing City, Fujian Province, P.R. China
Equipment under Test	:	LCD Monitor
Model No.	:	25M2N32, 25M2N3200W, 25M***** ("*" = 0-9, A-Z, a-z, +, -, /, \ or blank)
Trade Mark	:	PHILIPS

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REPORT

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Annex A Test Setup Photos 54

Test Report Declare

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Test Standard Used:

EN 55032:2015, EN 55032:2015/A11:2020, EN 55032:2015/A1:2020,
CISPR 32:2015/AMD1:2019, AS/NZS CISPR 32:2015 AMD 1:2020
BS EN 55032:2015, BS EN 55032:2015+A11:2020, BS EN 55032:2015+A1:2020
EN 55035:2017, EN 55035:2017/A11:2020, CISPR 35:2016, BS EN 55035:2017
BS EN 55035:2017+A11:2020
EN 61000-3-2:2014, EN IEC 61000-3-2:2019/A1:2021, BS EN 61000-3-2:2014, BS EN IEC
61000-3-2:2019+A1:2021
EN 61000-3-3:2013, EN 61000-3-3:2013/A1:2019, EN 61000-3-3:2013/A2:2021, BS EN 61000-3-
3:2013, BS EN 61000-3-3:2013+A1:2019, BS EN 61000-3-3:2013/A2:2021

Test Procedure Used:

IEC 61000-4-2:2008, IEC 61000-4-3:2020, IEC 61000-4-4:2012,
IEC 61000-4-5:2014/AMD1:2017, IEC 61000-4-6:2013, IEC 61000-4-8:2009, IEC 61000-4-
11:2020

We Declare:

The equipment described above is tested and assessed by Tianjin Dongdian Testing Service Co., Ltd. and in the configuration assessed the equipment complied with the standards specified above. The tested and assessed results are contained in this test report and Tianjin Dongdian Testing Service Co., Ltd. is assumed of full responsibility for the accuracy and completeness of these assessments.

After test and evaluation, our opinion is that the equipment in accordance with above standards.

Report No.:	DDT-B23020606-1E01		
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Prepared By:

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Aaron Zhang

Aaron Zhang/EMC Manager

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Revision History

Rev.	Revisions	Issue Date	Revised By
---	Initial issue	Feb. 16, 2023	